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RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2133

PATENT APPLICATION
Docket No.: 9898-197
Client Ref. No. SS-15599-US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Heon-Deok PARK, et al.

Serial No.: 10/003,180 Examiner: Kerveros, James C.

Filed: October 30, 2001 Group Art Unit: 2133

Confirmation No.: 4103

For: SEMICONDUCTOR TEST SYSTEM AND METHOD FOR
EFFECTIVELY TESTING A SEMICONDUCTOR DEVICE
HAVING MANY PINS

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL REJECTION UNDER 37 CFR 1.116

Responsive to the Final Office Action, Paper No. 20050228, dated March 4, 2005,
please amend the application as follows.

Amendments to the Claims are reflected in the listing of claims which begins on
page 2 of this paper.

Remarks/Arguments begin on page 6 of this paper.